

제22회 한국반도체학술대회

2015년 2월 10일(화) - 12일(목), 인천 송도컨벤시아

G. Device & Process Modeling, Simulation and Reliability 분과

Room C
1F / 106호

2015년 2월 12일(목) 09:00-10:30

[TC1-G] Device Variability and Reliability

좌장: 박찬형 (광운대학교), 신민철 (KAIST)

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| TC1-G-1 | 09:00-09:15 | The Influence of Variability Sources on SRAM Stability in 90 Å Non-rectangular Bulk FinFET SRAM cell
Sung-Won Yoo, Young-Soo Seo, Do-Gyun Son, and Hyungcheol Shin
School of Electrical Engineering and Computer Science, Seoul National University |
| TC1-G-2 | 09:15-09:30 | Analysis of Structural Variation in 10-nm Double Gate-All-Around (D-GAA) Transistor with Asymmetric Channel Width
Myunghwan Ryu and Youngmin Kim
School of Electrical and Computer Engineering, Ulsan National Institute of Science and Technology |
| TC1-G-3 | 09:30-09:45 | Analysis of Current Fluctuation Due to Trap in Nano-scale Bulk FinFETs
Kyu-Bong Choi, Jongmin Shin, and Jong-Ho Lee
Department of ECE and ISRC, Seoul National University |
| TC1-G-4 | 09:45-10:00 | Hump Characteristics Generated by Bias Stress in a-IGZO TFTs
Jungmin Lee, Sungju Choi, Jaeyeop Ahn, Jun Seok Hwang, Seong Kwang Kim, Sung-Jin Choi, Dae Hwan Kim, and Dong Myong Kim
School of Electrical Engineering, Kookmin University |
| TC1-G-5 | 10:00-10:15 | The Statistical Distribution of Electrical Characteristics with Random Grain Boundary in Vertical NAND Unit Cells
Jungsik Kim ¹ , Bo Jin ¹ , Hyeongwan Oh ² , Chang-Ki Baek ³ , Jeong-Soo Lee ^{1,2}
¹ Department of IT Convergence Engineering, Pohang University of Science and Engineering, ² Electrical Engineering, Pohang University of Science and Engineering, ³ Creative IT Engineering and Future IT Innovation Lab, Pohang University of Science and Engineering |
| TC1-G-6 | 10:15-10:30 | Interconnect Line-Induced 1/f Noise in Printed Circuit Board (PCB)
Hyeong-Sub Song ¹ , Sung-Kyu Kwon ¹ , Jae-Nam Yu ² , Sun-Ho Oh ² , Jong-Chan Ahn ¹ , and Hi-Deok Lee ²
¹ Research Division, SMAT Solutions, ² Department of Electronic Engineering, Chungnam National University |